

<b>Notice of References Cited</b>	Application/Control No. 10/752,399	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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X	B	US-2002/0132116 a1	09-2002	Wandel et al.	428/364
X	C	US-2002/0147298 a1	10-2002	Sun et al.	528/310
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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